

Schedule of JEOL Papers and Posters at M&M 2014

Platform Session Monday 1:30 PM Marriott Ballroom B

2:45 PM **125 M&M Student Award** *Magnetic Imaging with a Novel Hole-Free Phase Plate*; S Pollard, Y Zhu; Brookhaven National Laboratory; M Malac; National Institute of Nanotechnology; M Beleggia; Technical University of Denmark; M Kawasaki; JEOL, Inc.

Poster Session Monday 3:30 PM Exhibit Hall AB

3:30 PM **18 SEM Image Observation Using an Electron Energy, and Electron Take-off Angle Filtered Detector**; T Otsuka, M Nakamura, K-I Yamashita, M Hara, K Honda, S-I Kitamura; JEOL Ltd.; F Timischl, M Kudo; JEOL Technics Ltd.
Poster # 2

Poster Session Monday 3:30 PM Exhibit Hall AB

3:30 PM **534 Accuracy of Strain in Strain Maps Improved by Averaging Multiple Maps**; N Endo, Y Kondo; JEOL Ltd.
Poster # 39

Poster Session Monday 3:30 PM Exhibit Hall AB

3:30 PM **565 Introduction of a New Conventional SEM: JSM-IT300LV: The Observation of a Water Containing Specimen with a Cooling Stage at 650 Pa**; N Inoue; JEOL Ltd.
Poster # 45

Poster Session Monday 3:30 PM Exhibit Hall AB

3:30 PM **576 A Double Silicon Drift Type Detector System for EDS with Ultrahigh Efficiency and Throughput for TEM**; S Kawai, I Onishi, T Ishikawa, K Yagi, T Iwama, K Miyatake, Y Iwasawa, M Matsushita, T Kaneyama, Y Kondo; JEOL Ltd.
Poster # 56

Platform Session Tuesday 10:30 AM Room: 24

11:00 AM **10 Ultra Low Voltage Secondary and Backscatter Imaging in FE-SEM – Successes and Challenges**; N Erdman, V Robertson, M Shibata; JEOL USA Inc

Poster Session Tuesday 10:30 AM Room: 21

10:45 AM **486 M&M Student Award** *The Atmospheric Scanning Electron Microscope (ASEM) Observes Axonal Segmentation and Synaptic Induction in Solution*; C Sato, M Sato, T Ebihara; National Institute of Industrial Science and Technology; T Kinoshita, K Hiarno, S Nishihara; Soka University; T Uemura; Shinshu University School of Medicine; H Nishiyama, M Suga; JEOL Ltd.

Platform Session Tuesday 10:30 AM Room: 25

10:30 AM **558 Image Collection using an Auto Data Acquisition System and An Application to Ice Embedded Ribosome**; Y Aoyama; JEOL, Ltd.

Platform Session Tuesday 3:30 PM Exhibit Hall AB

3:30 PM **62 Resolving 45 pm with 300 kV Aberration Corrected STEM**; H Sawada, N Shimura, K Satoh, E Okunishi, F Hosokawa; JEOL Ltd., Japan; N Shibata, Y Ikuhara; The University of Tokyo
Poster # 127

3:30 PM **243 An advanced quantitative analysis of Li in LIB with AES Preparation for a clean cross section with the Cross Section Polisher**; A Tanaka, K Tsutsumi, H Onodera, T Tazawa; JEOL Ltd.
Poster # 135

Poster Session Tuesday 3:30 PM Exhibit Hall AB

3:30 PM **244** *Quantitative oxidation state analysis of transition metals in a lithium-ion battery with high energy resolution AES*; A Tanaka, K Tsutsumi, H Onodera, T Tazawa; JEOL Ltd.
Poster # **136**

Poster Session Tuesday 3:30 PM Exhibit Hall AB

3:30 PM **860** *2013 Vicência Meteorite Found in Brazil: Preliminary Classification Efforts Based on Traditional Approaches and Cathodoluminescence (CL) Maps*; B Leite; JEOL USA Inc.
Poster # **222**

Platform Session Wednesday 8:30 AM Room: 11

9:45 AM **187** *Generalised Holography Meets Coherent Diffractive Imaging*; AJ D'Alfonso, AJ Morgan, AW Yan, LJ Allen; University of Melbourne; P Wang; Nanjing University; H Sawada; JEOL; AI Kirkland; University of Oxford

Platform Session Wednesday 8:30 AM Room: 24

9:00 AM **341** (Invited) *Present State of TEM-SXES Analysis and its Application to SEM aiming Chemical Analysis of Bulk Materials*; H Takahashi, N Handa, T Murano; JEOL, Ltd.; M Koike, T Imazono; Japan Atomic Energy Agency; M Koeda, T Nagano, H Sasai, Y Oue, Z Yonezawa, S Kuramoto; Shimadzu Corp.

9:45 AM **343** *Recent Achievement of Electron Beam Deceleration Method for FE-SEM Enhanced Elemental Analysis including Soft X-ray Emission Spectroscopy*; S Asahina, Y Sakuda, T Murano, H Takahashi, N Kikuchi, K Kawauchi, T Nokuo; JEOL, Ltd.; F Schüth; Max-Planck-Institut für Kohlenforschung; O Terasaki; Stockholm University

Platform Session Wednesday 10:30 AM Room: 11

11:15 AM **190** *Resolution Enhancement at Low-Accelerating-Voltage by Improvements of Diffraction Limit and Chromatic Aberration*; T Sasaki, H Sawada, F Hosokawa; JEOL, Ltd.; K Suenaga; National Institute of Advanced Industrial Science and Technology

Poster Session Wednesday 10:30 AM Room: 12

11:00 AM **319** *Ultra High Solid Angle EDS System Advanced STEM Analysis for FE-SEM*; Y Nakajima, N Kikuchi, S Asahina, K Kawauchi, T Nokuo; JEOL Ltd.; M Suzuki; Thermo Fisher Scientific; N Erdman, M Shibata; JEOL USA, Inc.

Platform Session Wednesday 10:30 AM Room: 24

10:30 AM **344** (Invited) *Strategies for Low Accelerating Voltage X-ray Microanalysis of Sub-Micrometer Features with the FE-EPMA*; P McSwiggen; McSwiggen & Associates; JT Armstrong; Carnegie Institution of Washington; C Nielsen; JEOL, Inc.

Platform Session Wednesday 1:30 PM Room: 12

1:45 PM **323** *Investigation of Multiple, Large Area EDS Detectors on an SEM Capable of Various Mounting Geometries for Optimal EDS Analysis*; D Edwards, D Guarrera, N Erdman, V Robertson; JEOL USA; N Rowlands, R McLaughlin; Oxford Instruments

Platform Session Wednesday 3:30 PM Exhibit Hall AB

3:30 PM **303** *Monochromator for Aberration-Corrected STEM*; M Mukai, E Okunishi, M Ashino, K Omoto, T Fukuda, A Ikeda, K Somehara, T Kaneyama; JEOL Ltd.; T Saitoh, T Hirayama; Japan Fine Ceramics Center; Y Ikuhara; The University of Tokyo
Poster # **273**

Poster Session Wednesday 3:30 PM Exhibit Hall AB

3:30 PM **371** *Development of an Automated Phase Analysis Procedure for Multi-Component Samples in EPMA*; N Mori, N Kato, S Honda, S Sakamoto, M Takakura; JEOL, Ltd.; P McSwiggen; McSwiggen & Associates; C Nielsen; JEOL, Inc.
Poster # **290**

Platform Session Thursday 8:30 AM Room: 22

9:15 AM **293** *Atomic Column Elemental Mapping by STEM-Moiré Method*; E Okunishi, N Endo, Y Kondo; JEOL Ltd.

Platform Session Thursday 8:30 AM Marriott Ballroom A

9:00 AM **963** *Multilayered Cr(Al)N/SiO_x Nanocomposite Coatings Fabricated by Differential Pumping Cosputtering*; M Kawasaki; JEOL USA Inc.; M Nose; University of Toyama; I Onishi; JEOL Ltd.; M Shiojiri; Kyoto Institute of Technology

Poster Session Thursday 10:30 AM Exhibit Hall AB

10:31 AM **438** *Precession Electron Diffraction Detection and Phase Mapping of Retained Austenite and Carbides in a Heat Treated Low Alloy Carbon Steel Using a JEOL ARM 200 TEM with an AppFive Topspin System for Synchronized Beam Scanning and Precession*; A Darbal; AppFive LLC
Poster # **412**

Poster Session Thursday 10:30 AM Exhibit Hall AB

10:30 AM **459** *The Present State of Chemical State Analysis in EPMA and WD-SXES*; N Mori, T Murano, H Takahashi; JEOL Ltd.
Poster # **422**

Platform Session Thursday 1:30 PM Room: 23

2:15 PM **111** (Invited) *High Throughput Fabrication Process of a Zernike Phase Plate*; Y Konyuba, H Iijima, M Suga, Y Ohkura; JEOL Ltd.; Y Abe; Yamagata Research Institute of Technology
2:45 PM **112** *First Demonstration of Phase Contrast Scanning Transmission Electron Microscopy*; H Minoda, T Tamai; Tokyo University of Agriculture and Technology; H Iijima, F Hosokawa, Y Kondo; JEOL Ltd.

Platform Session Thursday 1:30 PM Marriott Ballroom B

2:00 PM **432** *Nanoscale Crystallographic Analysis in FE-SEM Using Transmission Kikuchi Diffraction*; N Erdman, M Shibata; JEOL USA Inc; T Nylese; EDAX, Inc.

Platform Session Thursday 3:30 PM Room: 23

4:15 PM **115** (Invited) *Charging of Thin-Film Phase Plates under Electron Beam Irradiation*; M Malac, M Bergen; National Institute for Nanotechnology; M Beleggia; Technical University of Denmark; RF Egerton; University of Alberta; M Kawasaki, K Motoki; JEOL USA; Y Okura, I Ishikawa; JEOL Ltd.